



S/N 09/633,375

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Daniel R. Loughmiller et al.

Examiner: Unknown

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Group Art Unit: 2812

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Title: CIRCUIT AND METHOD FOR MEASURING AND FORCING AN  
INTERNAL VOLTAGE OF AN INTEGRATED CIRCUIT

PATENT PreAmend

4/13/01  
APC

**SUPPLEMENTAL PRELIMINARY AMENDMENT**

Commissioner for Patents  
Washington, D.C. 20231

Before taking up the above-identified application for examination, please enter the following amendments.

**IN THE CLAIMS**

Please cancel claim 1 after adding the following new claims:

**RECEIVED**

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19. (New) A method for measuring a voltage at an internal node of an integrated circuit, the method comprising:

coupling a pass circuit between the internal node and a pin of the integrated circuit;  
using a reset circuit to activate the pass circuit; and  
driving the pass circuit to pass the voltage from the internal node to the pin.

20. (New) The method of claim 19, further comprising using a pass control circuit to drive the pass circuit.

21. (New) The method of claim 20, further comprising using the pass control circuit to provide at least one output signal to selectively drive the pass circuit to pass a voltage from the internal node to the pin, thereby allowing the voltage at the internal node to be read after the integrated circuit is packaged.

22. (New) The method of claim 20, wherein the pass control circuit comprises an n-channel MOS transistor having a drain coupled to the internal node, the n-channel MOS transistor configured to, when turned on, pass the voltage at the internal node to a source of the n-channel MOS transistor and to the pass circuit.